

September 22-26 2009, Palma de Mallorca, Spain

TRACK CO-CHAIRS

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Track 5. INDUSTRIAL CONTROL

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Sponsored by: Technical University of Catalonia (UPC), University of
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This track will focus on the critical issues in industrial control. At the tool and process level, there are new methods and capabilities required to effectively use process and product measurements to impart control. Industrial control addresses the use of sensors, metrology, and algorithms to monitor equipment, processes and products to provide actionable information for maintenance and control. The successful application of industrial control draws from the domain expertise of multiple disciplines that are typically responsible for delivering separate elements of the complete solution such as IT/Factory Automation, Process Technology, Control Engineering, Yield Management, Metrology, etc.

Topics of Special Interest include but are not limited to

- Process Control
- Equipment Control
- Intelligent Control
- Supervisory Control
- Industrial Control Implementation
- Discrete and Continuous Automation System
- Equipment and Process Monitoring
- Fault Detection and Classification
- Process Modelling and Optimization
- Process Control Application

SUBMISSION OF PAPERS

Papers are to be submitted electronically. For further details, please consult the conference web pages.

AUTHOR'S SCHEDULE

Deadline for submission of full papers:	April 30, 2009
Notification of papers acceptance:	June 8, 2009
Final manuscripts due:	July 5, 2009

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